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Application/Control No.	Applicant(s)/Patent under Reexamination
10/562,755	PYKE ET AL.
Examiner	Art Unit

James R. Bidwell

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SEARCHED				
Class	Subclass	Date	Examiner	
198	346.1			
	346.2			
	346.3			
	465.1			
	465.2			
	817	9/9/2006	JRB	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT	ES STRATEGY)
	DATE	EXMR
		